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Data Sheet

October 2013

N-Channel UltraFET Power MOSFET 55 V, 20 A, 26 mΩ

These N-Channel power MOSFETs are manufactured using the innovative UltraFET process. This advanced process technology achieves the lowest possible onresistance per silicon area, resulting in outstanding performance. This device is capable of withstanding high energy in the avalanche mode and the diode exhibits very low reverse recovery time and stored charge. It was designed for use in applications where power efficiency is important, such as switching regulators, switching converters, motor drivers, relay drivers, low-voltage bus switches, and power management in portable and batteryoperated products.

Formerly developmental type TA75329.

Ordering Information

PART NUMBER	PACKAGE	BRAND
HUF75329D3ST	TO-252AA	75329D

Features

- 20A, 55V
- Simulation Models
 - Temperature Compensated PSPICE® and SABER™ Models
 - SPICE and SABER Thermal Impedance Models Available on the WEB at: www.fairchildsemi.com
- Peak Current vs Pulse Width Curve
- UIS Rating Curve
- Related Literature

Symbol

- TB334, "Guidelines for Soldering Surface Mount Components to PC Boards"



Packaging

JEDEC TO-252AA



Product reliability information can be found at http://www.fairchildsemi.com/products/discrete/reliability/index.html For severe environments, see our Automotive HUFA series.

All Fairchild semiconductor products are manufactured, assembled and tested under ISO9000 and QS9000 quality systems certification.

Absolute Maximum Ratings $T_C = 25^{\circ}C$, Unless Otherwise Specified

		UNITS
Drain to Source Voltage (Note 1) V _{DSS}	55	V
Drain to Gate Voltage (R _{GS} = 20kΩ) (Note 1) V _{DGR}	55	V
Gate to Source Voltage	±20	V
Drain Current		
Continuous (Figure 2)	20	А
Pulsed Drain Current	Figure 4	
Pulsed Avalanche Rating E _{AS}	Figure 6	
Power Dissipation	128	W
Derate Above 25 ^o C	0.86	W/ ^o C
Operating and Storage Temperature	-55 to 175	°C
Maximum Temperature for Soldering		
Leads at 0.063in (1.6mm) from Case for 10s	300	°C
Package Body for 10s, See Techbrief 334	260	°C

CAUTION: Stresses above those listed in "Absolute Maximum Ratings" may cause permanent damage to the device. This is a stress only rating and operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied.

NOTE:

1. $T_J = 25^{\circ}C$ to $150^{\circ}C$.

PARAMETER	SYMBOL	TEST CONDITIONS	MIN	TYP	MAX	UNITS
OFF STATE SPECIFICATIONS						
Drain to Source Breakdown Voltage	BV _{DSS}	$I_D = 250 \mu A$, $V_{GS} = 0V$ (Figure 11)	55	-	-	V
Zero Gate Voltage Drain Current	IDSS	$V_{DS} = 50V, V_{GS} = 0V$	-	-	1	μΑ
		$V_{DS} = 45V, V_{GS} = 0V, T_{C} = 150^{\circ}C$	-	-	250	μΑ
Gate to Source Leakage Current	I _{GSS}	$V_{GS} = \pm 20V$	-	-	±100	nA
ON STATE SPECIFICATIONS						
Gate to Source Threshold Voltage	V _{GS(TH)}	$V_{GS} = V_{DS}$, $I_D = 250 \mu A$ (Figure 10)	2	-	4	V
Drain to Source On Resistance	rDS(ON)	$I_D = 20A, V_{GS} = 10V$ (Figure 9)	-	0.022	0.026	Ω
THERMAL SPECIFICATIONS						
Thermal Resistance Junction to Case	R _{θJC}	(Figure 3)	-	-	1.17	°C/W
Thermal Resistance Junction to Ambient	R_{\thetaJA}	TO-252	-	-	100	°C/W
SWITCHING SPECIFICATIONS (V _{GS} = 10)	/)			4		
Turn-On Time	tON	$V_{DD} = 30V, I_D \cong 20A,$	-	-	60	ns
Turn-On Delay Time	t _d (ON)	R _L = 1.5Ω, V _{GS} = 10V, R _{GS} = 9.1Ω	-	7	-	ns
Rise Time	tr		-	30	-	ns
Turn-Off Delay Time	t _{d(OFF)}		-	10	-	ns
Fall Time	t _f		- /	33	-	ns
Turn-Off Time	tOFF	1	-	-	65	ns
GATE CHARGE SPECIFICATIONS						

 $V_{GS} = 0V$ to 10V

 $V_{GS} = 0V$ to 2V

Q_{g(10)}

 $Q_{g(TH)}$

Qgs

Q_{gd}

 $I_D \cong 20A,$ $R_L = 1.5\Omega$

(Figure 13)

 $I_{g(REF)} = 1.0 \text{mA}$

Gate Charge at 10V

Threshold Gate Charge

Gate to Source Gate Charge

Reverse Transfer Capacitance

nC

nC

nC

nC

32

2.0

5

13

-

-

-

-

40

2.5

-

-

Electrical Specifications $T_C = 25^{\circ}C$, Unless Otherwise Specified

PARAMETER	SYMBOL	TEST CONDITIONS	MIN	TYP	MAX	UNITS
CAPACITANCE SPECIFICATIONS						
Input Capacitance	C _{ISS}	$V_{DS} = 25V, V_{GS} = 0V,$	-	1060	-	pF
Output Capacitance	C _{OSS}	f = 1MHz (Figure 12)	-	405	-	pF
Reverse Transfer Capacitance	C _{RSS}		-	95	-	pF

Source to Drain Diode Specifications

PARAMETER	SYMBOL	TEST CONDITIONS	MIN	TYP	MAX	UNITS
Source to Drain Diode Voltage	V _{SD}	I _{SD} = 20A	-	-	1.25	V
Reverse Recovery Time	t _{rr}	$I_{SD} = 20A$, $dI_{SD}/dt = 100A/\mu s$	-	-	68	ns
Reverse Recovered Charge	Q _{RR}	$I_{SD} = 20A$, $dI_{SD}/dt = 100A/\mu s$	-	-	120	nC

Typical Performance Curves

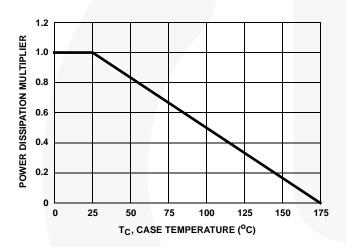


FIGURE 1. NORMALIZED POWER DISSIPATION vs CASE TEMPERATURE

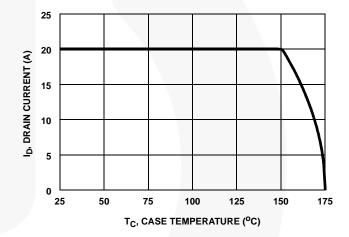
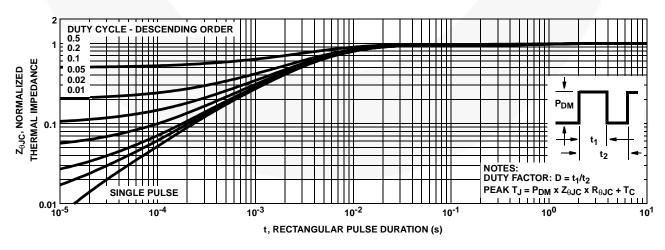
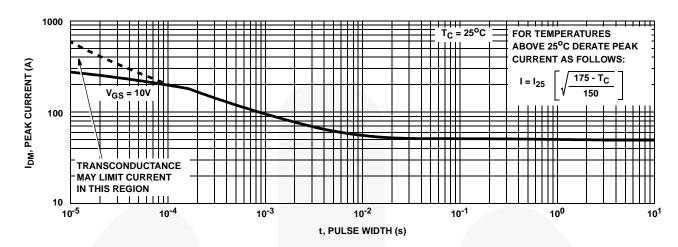


FIGURE 2. MAXIMUM CONTINUOUS DRAIN CURRENT vs CASE TEMPERATURE











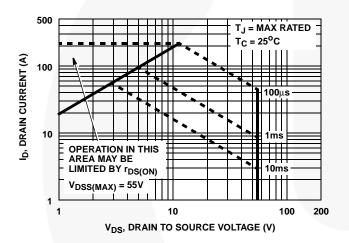


FIGURE 5. FORWARD BIAS SAFE OPERATING AREA

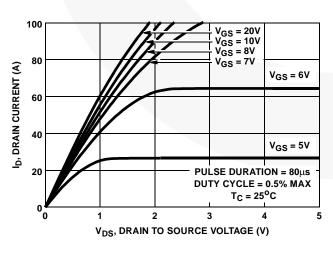
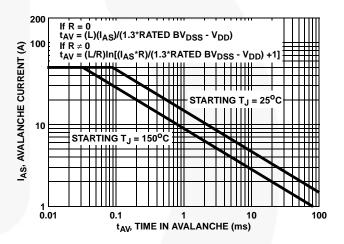


FIGURE 7. SATURATION CHARACTERISTICS



NOTE: Refer to Fairchild Application Notes AN9321 and AN9322. FIGURE 6. UNCLAMPED INDUCTIVE SWITCHING CAPABILITY

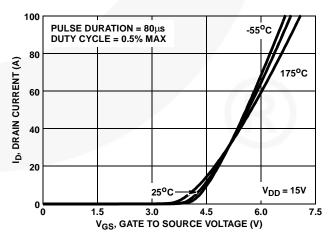
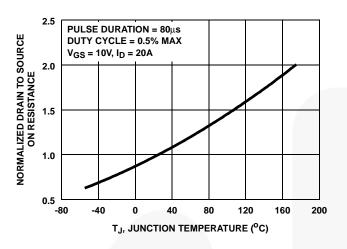


FIGURE 8. TRANSFER CHARACTERISTICS

Typical Performance Curves (Continued)





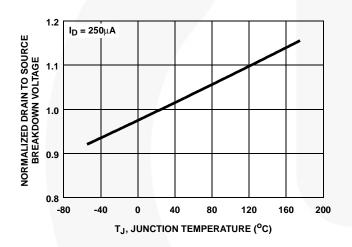
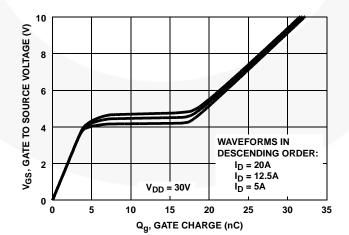


FIGURE 11. NORMALIZED DRAIN TO SOURCE BREAKDOWN VOLTAGE vs JUNCTION TEMPERATURE





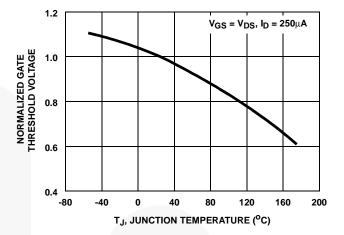
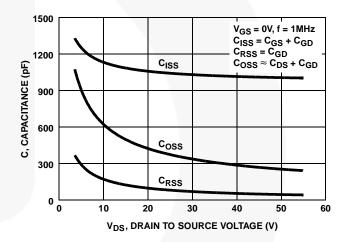


FIGURE 10. NORMALIZED GATE THRESHOLD VOLTAGE vs JUNCTION TEMPERATURE





Test Circuits and Waveforms

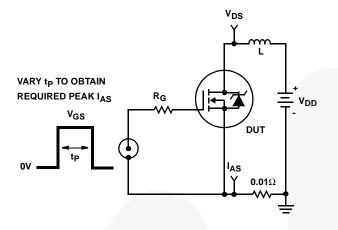


FIGURE 14. UNCLAMPED ENERGY TEST CIRCUIT

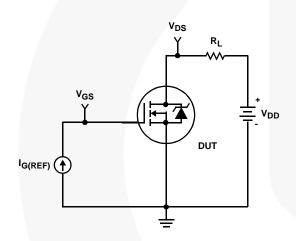


FIGURE 16. GATE CHARGE TEST CIRCUIT

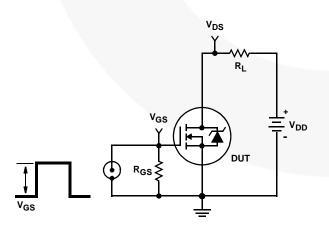


FIGURE 18. SWITCHING TIME TEST CIRCUIT

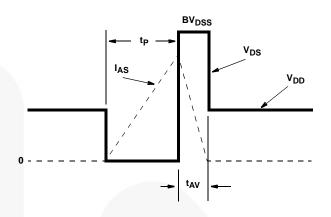
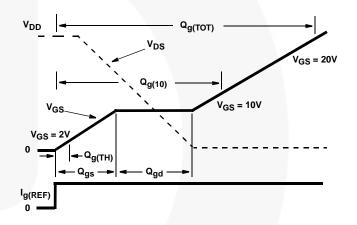


FIGURE 15. UNCLAMPED ENERGY WAVEFORMS





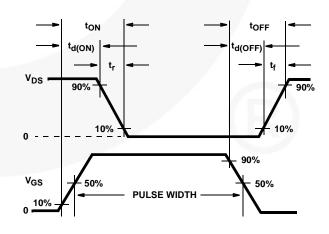
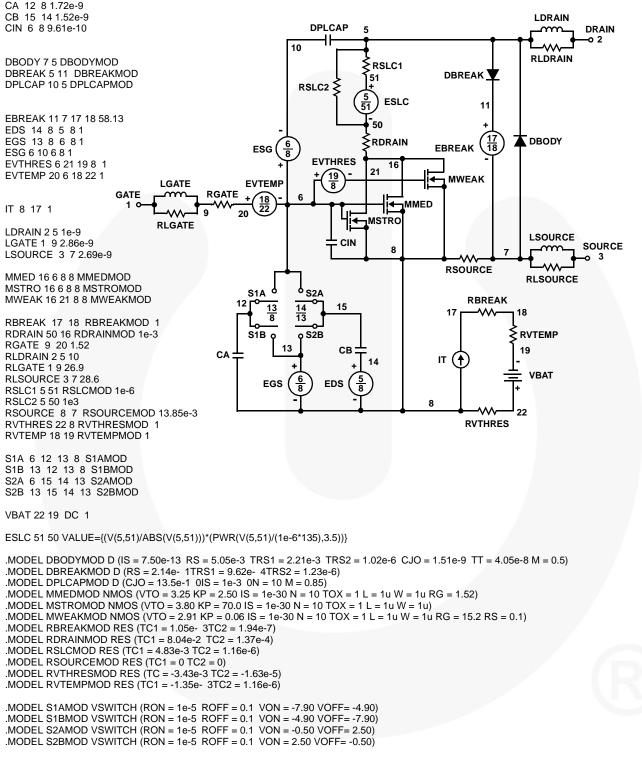


FIGURE 19. RESISTIVE SWITCHING WAVEFORMS

PSPICE Electrical Model

.SUBCKT HUF75329D 2 1 3 ; rev 6/19/97



.ENDS

NOTE: For further discussion of the PSPICE model, consult **A New PSPICE Sub-Circuit for the Power MOSFET Featuring Global Temperature Options**; IEEE Power Electronics Specialist Conference Records, 1991, written by William J. Hepp and C. Frank Wheatley.

SABER Electrical Model

REV June 1997 template huf75329d n2, n1, n3 electrical n2, n1, n3 var i iscl d..model dbodymod = (is = 7.50e-13, cjo = 1.51e-9, tt = 4.05e-8, m = 0.5) d..model dbreakmod = () LDRAIN DPLCAP 5 DRAIN d..model dplcapmod = (cjo = 13.5e-10, is = 1e-30, n = 10, m = 0.85) m..model mmedmod = (type=_n, vto = 3.25, kp = 2.50, is = 1e-30, tox = 1) o 2 10 m..model mstrongmod = (type=_n, vto = 3.80, kp = 70, is = 1e-30, tox = 1) RLDRAIN m..model mweakmod = (type=_n, vto = 2.91, kp = 0.06, is = 1e-30, tox = 1) ≻RSLC1 RDBREAK sw_vcsp..model s1amod = (ron = 1e-5, roff = 0.1, von = -7.90, voff = -4.90) 51 RSLC2 sw vcsp..model s1bmod = (ron = 1e-5, roff = 0.1, von = -4.90, voff = -7.90) 72 RDBODY sw_vcsp..model s2amod = (ron = 1e-5, roff = 0.1, von = -0.50, voff = 2.50) Ŧ ISCL sw_vcsp..model s2bmod = (ron = 1e-5, roff = 0.1, von = 2.50, voff = -0.50) DBREAK 50 c.ca n12 n8 = 1.72e-9 71 RDRAIN <u>6</u> 8 c.cb n15 n14 = 1.52e-9 ESG 11 EVTHRES c.cin n6 n8 = 9.61e-10 16 21 <u>19</u> 8 MWEAK İ**∢** EVTEMP I GATE d.dbody n7 n71 = model=dbodymod DBODY RGATE GATE d.dbreak n72 n11 = model=dbreakmod 18 22 EBREAK I ← I MMED d.dplcap n10 n5 = model=dplcapmod 1 C 9 20 \sim Чi∢ MSTRO RLGATE i.it n8 n17 = 1 18 LSOURCE CIN SOURCE 8 I.Idrain n2 n5 = 1e-9 3 o l.lgate n1 n9 = 2.86e-9 RSOURCE RLSOURCE l.lsource n3 n7 = 2.69e-9 k.k1 i(l.lgate) i(l.lsource) = I(l.lgate), I(l.lsource), 0.0085 S1A RBREAK 15 <u>14</u> 13 17 \sim 18 m.mmed n16 n6 n8 n8 = model=mmedmod, I = 1u, w = 1u m.mstrong n16 n6 n8 n8 = model=mstrongmod, I = 1u, w = 1u RVTEMP o S2B S1B m.mweak n16 n21 n8 n8 = model=mweakmod, I = 1u, w = 1u CB 19 CA IT 14 res.rbreak n17 n18 = 1, tc1 = 1.05e-3, tc2 = 1.94e-7 res.rdbody n71 n5 = 5.05e-3, tc1 = 2.21e-3, tc2 = 1.02e-6 VBAT FGS 8 5 FDS res.rdbreak n72 n5 = 2.14e-1, tc1 = 9.62e-4, tc2 = 1.23e-6 res.rdrain n50 n16 = 1e-3, tc1 = 8.04e-2, tc2 = 1.37e-4 8 res.rgate n9 n20 = 1.52 22 res.rldrain n2 n5 = 10 RVTHRES res.rlgate n1 n9 = 26.9 res.rlsource n3 n7 = 28.6 res.rslc1 n5 n51 = 1e-6, tc1 = 4.83e-3, tc2 = 1.16e-6 res.rslc2 n5 n50 = 1e3 res.rsource n8 n7 = 13.85e-3, tc1 = 0, tc2 = 0 res.rvtemp n18 n19 = 1, tc1 = -1.35e-3, tc2 = 1.16e-6 res.rvthres n22 n8 = 1, tc1 = -3.43e-3, tc2 = -1.63e-5 spe.ebreak n11 n7 n17 n18 = 58.13 spe.eds n14 n8 n5 n8 = 1 spe.egs n13 n8 n6 n8 = 1 spe.esg n6 n10 n6 n8 = 1 spe.evtemp n20 n6 n18 n22 = 1 spe.evthres n6 n21 n19 n8 = 1 sw_vcsp.s1a n6 n12 n13 n8 = model=s1amod sw_vcsp.s1b n13 n12 n13 n8 = model=s1bmod sw_vcsp.s2a n6 n15 n14 n13 = model=s2amod sw_vcsp.s2b n13 n15 n14 n13 = model=s2bmod v.vbat n22 n19 = dc = 1 equations { i(n51->n50) + = iscliscl: v(n51,n50) = ((v(n5,n51)/(1e-9+abs(v(n5,n51))))*((abs(v(n5,n51)*1e6/135))**3.5)))

SPICE Thermal Model

REV 23 February 1999

HUF75329D

CTHERM1 th 6 2.80e-3 CTHERM2 6 5 1.00e-2 CTHERM3 5 4 6.80e-3 CTHERM4 4 3 7.00e-3 CTHERM5 3 2 1.60e-2 CTHERM6 2 tl 15.55

RTHERM1 th 6 7.94e-3 RTHERM2 6 5 1.98e-2 RTHERM3 5 4 5.57e-2 RTHERM4 4 3 3.13e-1 RTHERM5 3 2 4.71e-1 RTHERM6 2 tl 6.26e-2

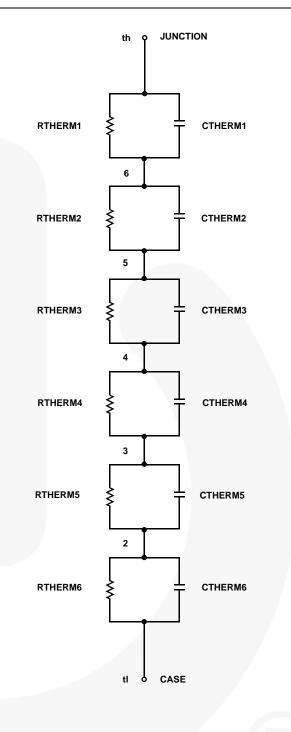
SABER Thermal Model

SABER thermal model HUF75329D

template thermal_model th tl thermal_c th, tl

ctherm.ctherm1 th 6 = 2.80e-3ctherm.ctherm2 6 5 = 1.00e-2ctherm.ctherm3 5 4 = 6.80e-3ctherm.ctherm4 4 3 = 7.00e-3ctherm.ctherm5 3 2 = 1.60e-2ctherm.ctherm6 2 tl = 15.55

rtherm.rtherm1 th 6 = 7.94e-3 rtherm.rtherm2 6 5 = 1.98e-2 rtherm.rtherm3 5 4 = 5.57e-2 rtherm.rtherm4 4 3 = 3.13e-1 rtherm.rtherm5 3 2 = 4.71e-1 rtherm.rtherm6 2 tl = 6.26e-2 }



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